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**RESPONSE UNDER 37 C.F.R. § 1.116  
EXPEDITED PROCEDURE REQUESTED  
EXAMINING GROUP 2123**

**PATENT**

Customer No. 22,852

Attorney Docket No. 04173.0441

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of:	)	
	)	
Hisashi Kaneko et al.	)	Group Art Unit: 2123
	)	
Application No.: 10/757,415	)	Examiner: Sharon, Ayal I
	)	
Filed: January 15, 2004	)	Confirmation No. 3384
	)	
For: SIMULATION CIRCUIT	)	<b>Mail Stop AF</b>
PATTERN EVALUATION	)	
METHOD, MANUFACTURING	)	
METHOD OF SEMICONDUCTOR	)	
INTEGRATE CIRCUIT, TEST	)	
SUBSTRATE, AND TEST	)	
SUBSTRATE GROUP	)	

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

**AMENDMENT AFTER FINAL**

In reply to the Final Office Action mailed May 22, 2007, the period for response being on August 22, 2007, and pursuant to 37 C.F.R. § 1.116, Applicants propose that this application be amended as follows:

**Amendments to the Claims** are reflected in the listing of claims beginning on page 2 of this paper.

**Remarks** begin on page 7 of this paper.